

May 2001

FQT5N20

200V N-Channel MOSFET

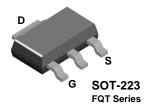
General Description

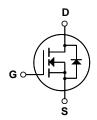
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply, DC-AC converters for uninterrupted power supply, motor control.

Features

- 1.0A, 200V, $R_{DS(on)}$ = 1.2 Ω @V_{GS} = 10 V Low gate charge (typical 6.0 nC)
- Low Crss (typical 6.0 pF)
- · Fast switching
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

	U				
Symbol	Parameter		FQT5N20	Units	
V _{DSS}	Drain-Source Voltage		200	V	
I _D	Drain Current - Continuous (T _C = 25°	C)	1.0	А	
	- Continuous (T _C = 70°	C)	0.8	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	4.0	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	60	mJ	
I _{AR}	Avalanche Current	(Note 1)	1.0	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	0.25	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		2.5	W	
	- Derate above 25°C		0.02	W/°C	
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	
.r					

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	200			V
ΔB _{VDSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		0.2		V/°C
I _{DSS}	7 0 . 1/1 5 . 0	V _{DS} = 200 V, V _{GS} = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 160 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics		•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 0.5 A		0.96	1.2	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 0.5 A (Note 4)		1.4		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		210 40 6	50 8	pF pF
	ing Characteristics			0	0	рі
t _{d(on)}	Turn-On Delay Time	V 400 V I 45 A		7	25	ns
t _r	Turn-On Rise Time	$V_{DD} = 100 \text{ V}, I_D = 4.5 \text{ A},$		55	120	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$		9	30	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		25	60	ns
Q _g	Total Gate Charge	V _{DS} = 160 V, I _D = 4.5 A,		6.0	7.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		1.5		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		2.2		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Dic	ode Forward Current			1.0	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				4.0	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.0 A			1.5	V
V SD						
trr	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 4.5 \text{ A},$		95		ns

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 90mH, I_{AS} = 1.0A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C 3. I_{SD} ≤ 4.5A, di/dt ≤ 300A/µs, V_{DD} ≤ BV_{DSS}, Starting T_{J} = 25°C 4. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

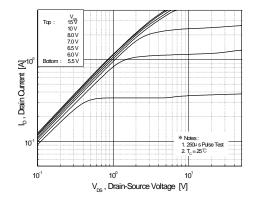


Figure 1. On-Region Characteristics

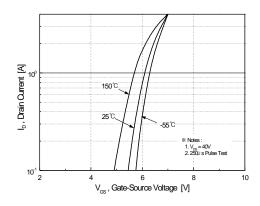


Figure 2. Transfer Characteristics

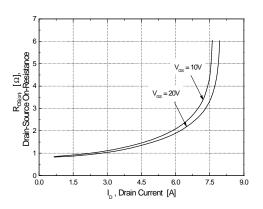


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

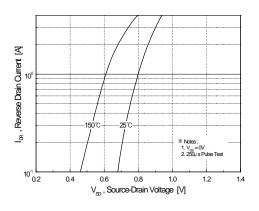


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

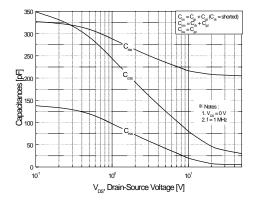


Figure 5. Capacitance Characteristics

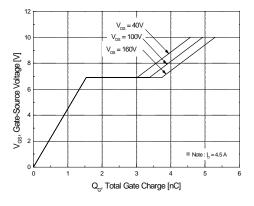
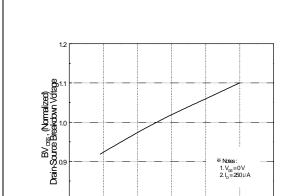


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

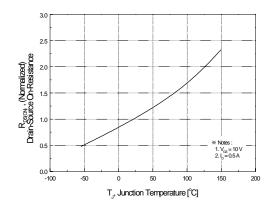
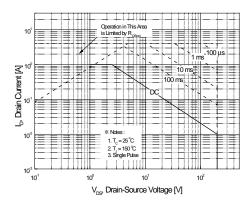


Figure 7. Breakdown Voltage Variation vs. Temperature

 $T_{_{\!J}}\!,$ Junction Temperature [°C]

Figure 8. On-Resistance Variation vs. Temperature



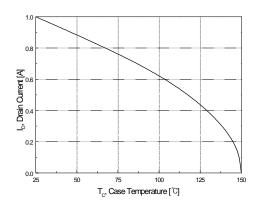


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

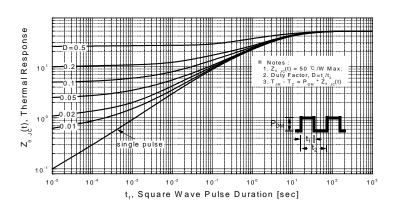
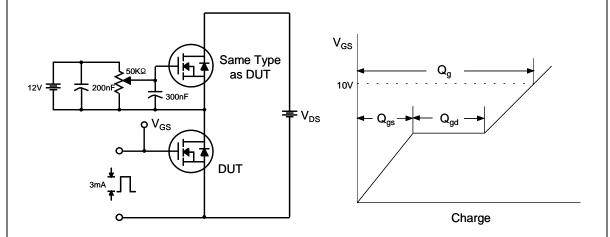


Figure 11. Transient Thermal Response Curve

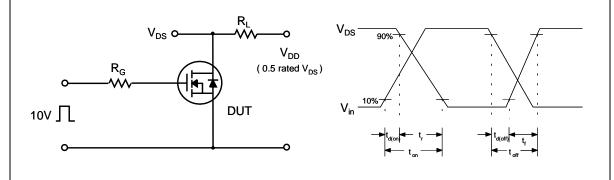
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(Note 4)
(Note 4, 5)
(Note 4)

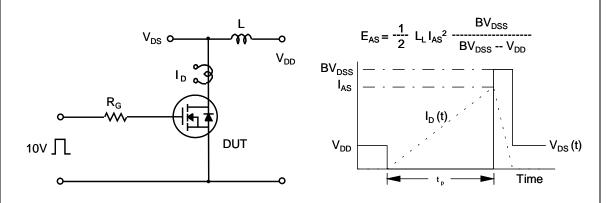
Gate Charge Test Circuit & Waveform



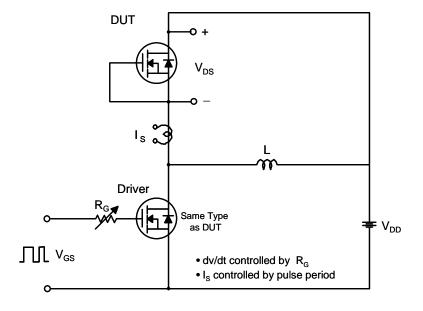
Resistive Switching Test Circuit & Waveforms

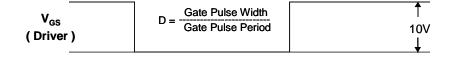


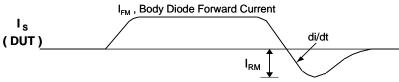
Unclamped Inductive Switching Test Circuit & Waveforms



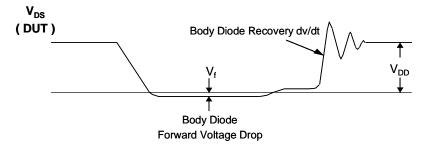
Peak Diode Recovery dv/dt Test Circuit & Waveforms

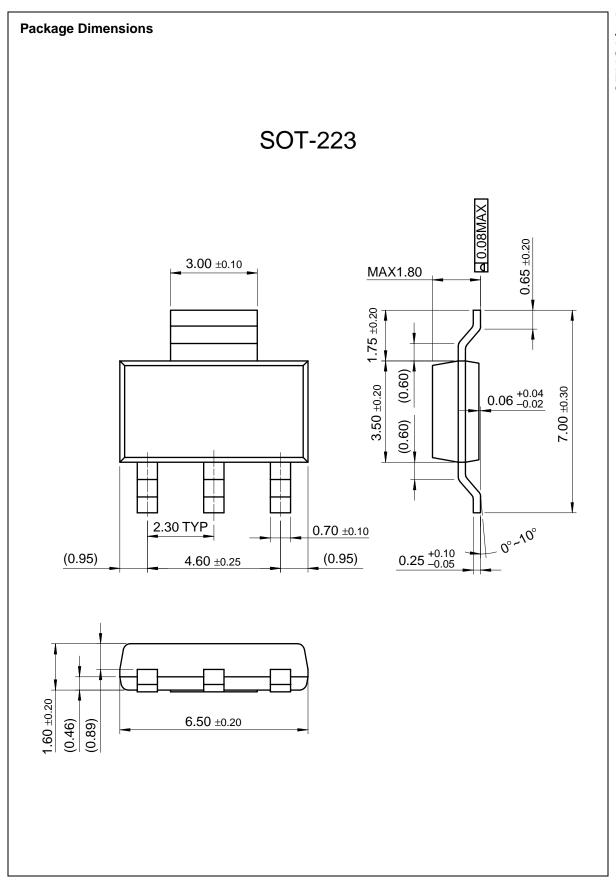






Body Diode Reverse Current





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